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(54) PRODUCTION OF METALLIC OXIDE THIN FILM

(57)Abstract:

PROBLEM TO BE SOLVED: To provide a method capable of forming thin film of crystallized transition metal oxide even on a substrate low in heat resistance such as plastics, free from the need of the use of expensive producing equipment and free from restriction by the shape and size of a substrate to be film-formed.

SOLUTION: The surface of the object to be coated is coated with a precursory coating soln. of metallic oxide obtd. by using the alkoxide of salt of transition metal as a starting raw material to form coating film on the surface of the object to be coated, and thereafter, the coating film is irradiated with ultraviolet light of ≥360 nm wavelength to crystallize the transition metal oxide forming the coating film.

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(54) 【発明の名称】金属酸化物薄膜の製造方法

(57)【要約】

【課題】 プラスチックスなどの耐熱性の低い基体上にも、結晶化した遷移金属酸化物の薄膜を形成でき、高価な製造設備を使用する必要も無く、成膜しようとする基体の形状や大きさにも制約されない方法を提供する。

【解決手段】 遅移金属のアルコキシドまたは塩を出発 駅料として得られる金属酸化物の前駆体銃布液を被銃布 物の表面に銃布して、被銃布物表面に銃布膜を形成した 後、その銃布膜に対して被長が360 nm以下である紫 外光を照射し、銃布膜を形成している遷移金属酸化物を 結晶化させる。

【特許請求の範囲】

【請求項1】 遷移金属のアルコキシドまたは塩を出発 原料として得られる金属酸化物の前駅体盤布液を被塗布 物の表面に釜布して、被釜布物表面に釜布膜を形成した 後、その釜布睒に対して波長が360nm以下である紫 外光を照射し、塗布膜を形成している遷移金属酸化物を 結晶化させることを特徴とする、金属酸化物薄膜の製造 方法。

【請求項2】 遷移金属が、IVa族元素またはVa族元 案である請求項1記載の、金風酸化物薄膜の製造方法。 釜布膜に対して照射する紫外光の光源 【請求項3】 が、高圧水銀ランプ、低圧水銀ランプ、ArFエキシマ レーザ、KrFエキシマレーザ、YAGレーザの4倍波 もしくは3倍波、エキシマランプまたはシンクロトロン 放射光である請求項1または請求項2記載の、金属酸化 物薄膜の製造方法。

【発明の詳細な説明】

[0001]

【発明の属する技術分野】この発明は、ガラス、セラミ ックス、金属、プラスチックス等の基板の表面に電子材 20 料などの機能性酸化物薄膜を形成する方法、特に、加熱 処理することなく結晶化された遷移金属酸化物の薄膜を 形成する金属酸化物薄膜の製造方法に関する。

[0002]

【従来の技術】遷移金風酸化物には、誘電材料、導電材 料、半導体材料などとして優れた電気特性を有する化合 物が多く存在する。これら遷移金属酸化物の薄膜は、ソ ルーゲル法、噴霧熱分解法、スパッタリング法、MOC VD法などにより製造される。

【0003】ゾルーゲル法による遷移金属酸化物薄膜の 製造方法に関しては、例えば、チタニア膜は、400℃ の温度でアナターゼが結晶化し、さらに800℃の温度 で加熱処理することによりルチル相へ転移することが知 られており、ジルコニア膜は、700℃の温度で加熱処 理することにより結晶化し(照菜協会誌、 9 4 、8 2 3 (1986) 参照)、酸化二オブ膜は、400℃の温度 で加熱処理することにより結晶化し(キャタリシス・ト off (Catalysis Today), 16,4 95 (1993) 参照)、酸化鉄膜は、450℃までの 温度でァー酸化鉄(ヘグマタイト)へ結晶化し、さらに 450℃以上の温度で加熱処理することによりα-酸化 鉄へ転移し(ジャーナル・オブ・マテリアル・サイエン ス (J. Mater. Sci.)、<u>26</u>、497 (19 91) 参照)、酸化亜鉛版は、400℃以上の温度で結 晶化すること(日本セラミックス協会学術論文誌、10 4、296 (1991) 参照) がそれぞれ報告されてい る。また、噴霧熱分解法による遷移金風酸化物薄膜の製 造方法に関しては、各種の金属塩を出発原料として酸化 鉄、クロミア、チタニア、ジルコニアなどの消じが形成

ムズ (Thin Solid Films)、<u>77</u>、8 1 (1981) 参照)。

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[0004]

【発明が解決しようとする課題】上記したように、一般 的なゾルーゲル法や噴霧分解法により遷移金属酸化物の **薄膜を形成する従来方法では、残留有機物や金属塩を熱** 分解して除去することが必要であり、その結果として、 金属酸化物を結晶化させるためには、400℃以上の高 温での加熱処理が必須である。このため、従来の方法に よっては、プラスチックスなどのような耐熱性の低い基 体上に、結晶化した選移金属酸化物の薄膜を形成するこ とができなかった。

【0005】また、スパッタリング法やMOCVD法 は、真空プロセスによるものであり、このため、高価な 製造設備が必要で、製造コストが高くなり、また、成膜 しようとする基体の形状や大きさに制約がある、といっ た問題点がある。また、これらの方法も、結晶性の金属 酸化物薄膜を得るためには、基板の加熱処理を必要とす る場合が多い。

【0006】この発明は、以上のような事情に鑑みてな されたものであり、プラスチックスなどの耐熱性の低い 基体上にも、結晶化した遷移金属酸化物の薄膜を形成す ることができ、高価な製造設備を使用する必要も無く、 また、成膜しようとする基体の形状や大きさにも制約さ れない金属酸化物薄膜の製造方法を提供することを目的 とする。

[00007]

【課題を解決するための手段】この発明では、上記目的 を達成するための手段として、ゾルーゲル法により形成 された遷移金風酸化物ゲルの薄膜を結晶化させるのに、 紫外光を利用するようにした。すなわち、請求項1に係 る発明は、遷移金属のアルコキシドまたは塩を出発原料 として得られる金属酸化物の前駆体釜布液を被釜布物の 表而に塗布して、被塗布物表面に塗布膜を形成した後、 その鈴布膜に対して波長が360nm以下である紫外光 を照射し、鎗布膜を形成している遷移金属酸化物を結晶 化させることを特徴とする。

【0008】請求項1に係る発明の製造方法では、遷移 金属のアルコキシドまたは塩を出発原料として得られる 金属酸化物の前駆体釜布液を被釜布物の表而に塗布し て、釜布膜を形成した後、その釜布膜に対して波長が3 60 nm以下である紫外光を照射することにより、 遷移 金属酸化物が結晶化される。したがって、遷移金属酸化 物の結晶化のために高温での加熱処理を行う必要が無い ので、プラスチックスのような耐熱性の低い基体上に も、結晶化した遷移金属酸化物の薄膜を形成することが 可能になる。なお、紫外光の照射による遷移金風酸化物 の結晶化のメカニズムは明確ではないが、紫外光を薄膜 が吸収し、そのエネルギーによって原子の再配列が進行 されることが報告されている(チン・ソリッド・フィル 50 させられ、遷移企風酸化物が結晶化するものと考えられ

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【0009】 請求項2に係る発明は、 請求項1 記載の製 造方法において、遷移金風がIVa族元素またはVa族元 素であることを特徴とする。

【0010】 節求項3に係る発明は、 節求項1または節 求項2記載の製造方法において、金属酸化物ゲルの范膜 に対して照射する紫外光の光源として、高圧水銀ラン プ、低圧水銀ランプ、ArFエキシマレーザ、KrFエ キシマレーザ、 YAGレーザの 4 倍波もしくは 3 倍波、 エキシマランプまたはシンクロトロン放射光を使用する ことを特徴とする。光源は、1種類のものだけを使用し ても、また2種以上のものを組み合わせて使用してもよ 11.

[0011]

【発明の実施の形態】以下、この発明の好適な実施形態 について説明する。

【0012】この発明に係る金属酸化物薄膜の製造方法 では、まず、遷移金属のアルコキシドまたは塩を出発原 料として、金属酸化物の前駆体塗布液(ソル)を調製す る。遷移金属は、例えばIVa族元素またはVa族元素で ある。塗布液の調製方法は特に限定されないが、塗布膜 (ゲル膜)を形成したときに、膜中の残留有機物が少な くなる程、また、加熱処理によるゲル膜の結晶化温度が 低くなる程好ましい。塗布液の調製方法を以下に説明す る。

【0013】出発原料として使用される金属アルコキシ ドとしては、アルコキシル基の炭素数が1~5であるも のが使用され、より好ましくはアルコキシル基の炭素数 が2~4のものが使用される。また、金属塩としては、 硝酸塩、塩化物などの無機塩、酢酸などの有機酸塩や、 アセチルアセトナートなどのβ-ジケトンの塩が使用さ れる。

【0014】金属アルコキシドまたは金属塩を溶解させ る溶剤としては、メタノール、エタノール、プロパノー ル、ブタノールなどのアルコール類、酢酸エチルなどの 有機酸エステル、アセトニトリル、アセトンやメチルエ チルケトンなどのケトン類、テトラヒドラフラン (TH F) やジオキサンなどのシクロエーテル、ホルムアミド (FA)、N、Nージメチルホルムアミド(DMF)な 使用される。

【0015】また、金属アルコキシドを含む溶液に、多 座配位化合物であるβ-ジケトン(RCOCH,CO R': R、R'はアルキル基またはアルコキシル基)、 アルコキシアルコール、アルカノールアミン、グリコー ル類、グリセリンなどを、アルコキシドの安定化の目的 で含まれるようにしてもよい。β-ジケトンとしては、 アセチルアセトン、アセト酢酸エチルやアセト酢酸メチ ルなどのアセト酢酸エステル、マロン酸ジエチルなどの マロン酸エステルなどが使用される。アルコキシアルコ 50 適宜選択される。換布觀に対して紫外光が照射されるこ

ールとしては、2-メトキシエタノール、2-エトキシ エタノール、2-メトキシ-2-プロパノールなどが使 用される。アルカノールアミンとしては、モノエタノー ルアミン、ジエタノールアミン、トリエタノールアミン などが使用される。グリコール類としては、エチレング リコール、ジエチレングリコール、トリエチレングリコ ールおよびプロピレングリコールやこれらの化合物のモ ノアルキルエーテルや酢酸エステルが使用される。これ らの化合物は単独で用いられあるいは併用され、その種 10 類は、金属種やアルコキシル基の種類により選定され る。また、これらの化合物は、アルコキシドの0.1モ ル倍~1.5モル倍の量が含まれることが望ましい。な お、アルコキシアルコール類は、溶媒として使用するこ とも可能である。

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【0016】金属アルコキシドまたは金属塩を含む溶液 の加水分解には、金属アルコキシドまたは金属塩の 0. 05モル倍~2モル倍の水が用いられ、より好ましく は、0.5モル倍~1.5モル倍の水が用いられる。こ の加水分解には、酸触媒および/または塩基触媒を用い るようにしてもよく、好ましくは、塩酸などの鉱酸や酢 酸などの有機酸が用いられる。なお、アルコキシドの種 類によっては、アルコキシドの希釈溶液が用いられる。 また、出発原料として金属塩を使用した場合には、アル コール系の溶剤との反応を有効に利用するようにする。 【0017】遷移金属のアルコキシドまたは塩を含む溶 液の加水分解によって金属酸化物の前駆体塗布液(ソ ル)が調製されると、その塗布液を基板の表面に塗布 し、それを乾燥させて基板表面に釜布膜(金属酸化物ゲ ル膜)を形成する。塗布液の塗布方法は、特に限定され 30 ず、通常行われるディップコート法、スピンコート法、 フローコート法、パーコート法、超音波噴霧法などが用 いられる。なお、このとき得られたゲル膜としては、上 記したように、その膜中の残留有機物量が少ない程、ま た、加熱処理した場合の結晶化温度が低い程好ましい。 【0018】基板表面に塗布膜が形成されると、その塗 布販に対して被長が360nm以下である紫外光を照射 する。紫外光の光源としては、波長が360nm以下で ある紫外光を照射可能であれば、その種類を問わず、目 的とする金属酸化物薄膜に応じて適宜選択して使用され どの酸アミド、炭化水素、トルエンなどの芳香族などが 40 るが、例えば、高圧水銀ランプ、低圧水銀ランプ、エキ シマランプ、ArFエキシマレーザ、KrFエキシマレ ーザ、YAGレーザ4倍波または3倍波、シンクロトロ ン放射光などが使用される。また、これらの光源のうち 2 つもしくはそれ以上のものを組み合わせて使用するこ とも可能である。この釜布膜に対する紫外光照射の際 に、目的に応じて、碁板を加熱したり、碁板を破圧下に 聞いたり、雰囲気(酸化雰囲気または非酸化雰囲気)を 制御したりすることも可能である。また、紫外光の照射 強度やショット数は、銃布膜の種類や組成などに応じて

とにより、釜布膜を形成している金属酸化物ゲルが結晶 化され、基板の表面に遷移金属酸化物の薄膜が形成され る。

[0019]

【実施例】次に、この発明を具体的に適用した実施例に ついて説明する。

【0020】〔実施例1〕ペンタエトキシタンタルを、 金属酸化物の固形分濃度が3重量%となるようにエタノ ールに溶解させて、釜布液を調製した。この釜布液を、 シリカ基板上に塗布した後、100℃の温度の乾燥器で 1時間乾燥させて、シリカ基板上に塗布膜を形成した。 得られた釜布膜に、ArFエキシマレーザ (193n m、25mJ/cm:、300ショット) を照射した。こ れにより、結晶性の酸化タンタル (Ta,O,) 薄膜が得 られた。得られた薄膜の薄膜X線回折パターンを図1に 示す。

【0021】〔実施例2〕ペンタエトキシニオブを、金 **风酸化物の固形分濃度が3重量%となるようにエタノー** ルに溶解させて、塗布液を調製した。この塗布液を、ス 20 :、100ショット)を照射した。これにより、立方晶 ピンコータ (2,000 r p m×15秒) を使用してシ リカ基板上に塗布した後、100℃の温度の乾燥器で1 時間乾燥させて、シリカ基板上に塗布膜を形成した。得 られた釜布膜に、ArFエキシマレーザ(193 nm、 2 5 m J / cm: 、3 0 0 ショット) を照射した。これに より、結晶性の酸化ニオブ(Nb,Oi)薄膜が得られ た。

【0022】 〔実施例3〕テトライソプロポキシチタン を2-メトキシエタノールに溶解させ、チタンと等モル 被に添加し、溶液を加水分解させて、塗布液を調製し た。この塗布液中の金属酸化物の固形分濃度は、3 重量 %となるようにした。この釜布液を、スピンコータ (2,000rpm×15秒)を使用してシリコン基板 上に銃布した後、100℃の温度の乾燥器で1時間乾燥 させて、シリコン基板上に塗布膜を形成した。得られた **塗布膜に、YAGレーザの4倍波(266nm、10m** J/cm,)を、照射ショット数を変化させて照射した。 これにより、ルチル(TiO:) 薄膜が得られた。 照射 折ピークが認められた。得られた薄膜の薄膜X線回折パ ターンの変化を図2に示す。

【0023】 [実施例4] 四塩化チタンを、金属酸化物 の間形分濃度が3重畳%となるように無水エタノールに 添加し、1日撹拌して溶解させ、釜布液を調製した。こ

の釜布液を、スピンコータ (2,000 r p m × 15 秒)を使用してシリコン基板上に鑑布した後、100℃ の温度の乾燥器で1時間乾燥させて、シリコン基板上に **釜布膜を形成した。得られた釜布膜に、YAGレーザの** 4倍波(266nm、10mJ/cm:、300ショッ ト)を照射した。これにより、上記した実施例3と同様 にルチル (TiO:) 薄膜が得られた。

【0024】〔実施例5〕テトラノルマルプトキシジル コニウムを2-メトキシエタノールに溶解させ、ジルコ スピンコータ (2,000 rpm×15秒)を使用して 10 ニウムと等モルのアセチルアセトンを2-メトキシエタ ノール溶液に添加し、さらに、ジルコニウムと等モルの 水を含む 0. 1 規定塩酸を 2 - メトキシエタノール 溶液 に添加し、溶液を加水分解させて、釜布液を調製した。 この塗布液中の金属酸化物の固形分濃度は、3重量%と なるようにした。この釜布液を、スピンコータ(2、0 00 r p m×15秒)を使用してシリコン基板上に塗布 した後、100℃の温度の乾燥器で1時間乾燥させて、 シリコン基板上に塗布膜を形成した。得られた塗布膜 に、ArFエキシマレーザ(193nm、25mJ/cm のジルコニア(ZrO:)薄膜が得られた。さらに、塗 布膜にArFエキシマレーザを1,000ショット照射 することにより、ジルコニアの高温相である単斜晶が認 められた。得られた薄膜の薄膜X線回折パターンの変化 を図3に示す。

【0025】〔実施例6〕ジルコニウムテトラアセチル アセトナートを、金属酸化物の固形分濃度が3重量%と なるようにメタノールに溶解させて、塗布液を調製し た。この塗布液を、スピンコータ (2,000 r p m × の水を含む 0. 1 規定塩酸を 2 - メトキシエタノール浴 30 15秒)を使用してシリコン基板上に釜布した後、湿度 60%の雰囲気中に3時間放置し、その後に100℃の 温度のオープンで1時間乾燥させて、シリコン基板上に 銃布膜を形成した。得られた塗布膜に、ArFエキシマ レーザ(1 9 3 n m、 2 5 m J / cm:、 1, 0 0 0 ショ ット)を照射した。これにより、上配した実施例 5 と同 様に立方晶および単斜晶のジルコニア (2 r O,) 薄膜 が得られた。

【0026】 [比較例1~6] 上配した実施例1~6に おいて得られた途布膜(金属酸化物ゲル膜)を加熱処理 ショット数が100ショットであったときに、ルチル回 40 することにより、結晶性の金属酸化物薄膜を作製した。 このときのそれぞれの加熱処理温度と得られた結晶相を 表1にまとめて示す。

[0027]

【表1】

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| | 加熱処理温度(℃) | 船 晶 相 |
|-------|----------------|----------------------|
| 比較例 1 | 4 5 0 | Ta:0. |
| 比較例 2 | 450 | Nb.O. |
| 比較例3 | 4 0 0 7 0 0 | アナターゼ ルチル単相 |
| 比較例4 | 5 0 0 7 0 0 | アナターゼ ルチル単相 |
| 比較例 5 | 5 0 0 8 0 0 | 立方品ジルコニア 単斜品ジルコニア |
| 比較例6 | 500 | 立方品ジルコニア |

【0028】表1から分かるように、結晶性の金属酸化 物薄膜を得るためには、400℃以上の温度での加熱処 理が必要であった。特に、実施例3~実施例6でそれぞ れ得られたルチル単相膜や単斜晶ジルコニア膜を得るた めには、700℃以上の温度での加熱処理が必要であっ た。

移金属酸化物薄膜の形成に限定されるものではなく、上 記以外の遷移金属酸化物薄膜を加熱処理なしで形成する 場合にも適用可能であることは言うまでもない。このよ うに、加熱処理を行わずに結晶性の遷移金属酸化物薄膜 を形成することができるので、この発明の方法による と、従来方法では不可能であったプラスチックス等の耐 熱性に劣る基板上に遷移金属酸化物薄膜を形成すること・ ができ、また、有機物を含む多層膜における遷移金属酸 化物薄膜の形成も可能になる。

[0030]

【発明の効果】請求項1ないし請求項3に係る発明の製

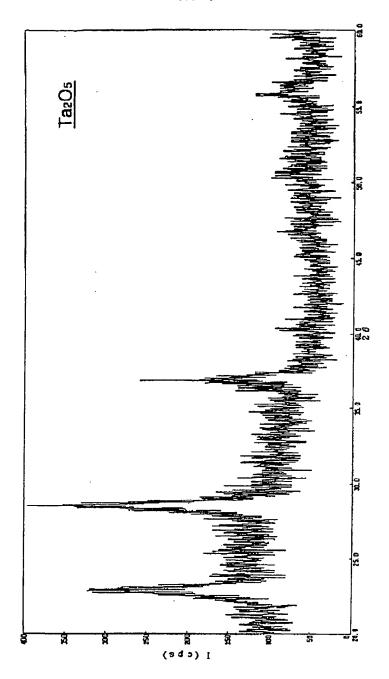
造方法によると、結晶化した遷移金属酸化物の薄膜を室 温付近の温度で得ることができる。したがって、プラス チックスなどの耐熱性の低い基板上にも、結晶性の遷移 金属酸化物薄膜を形成することが可能である。また、こ の製造方法を実施するために、高価な製造設備を使用す る必要は無く、従って製造コストを低く抑えることがで 【0029】なお、この発明は、上記実施例で示した選 20 き、また、成膜しようとする基体の形状や大きさに制約 されることもない。

【図面の簡単な説明】

【図1】この発明に係る製造方法によって得られた酸化 タンタル薄膜の薄膜X線回折パターンを示す図である。 【図2】同じく、この発明に係る製造方法によって得ら れたルチル薄膜の薄膜X線回折パターンの変化を示す図 である。

【図3】同じく、この発明に係る製造方法によって得ら れたジルコニア薄膜の薄膜X線回折パターンの変化を示 30 す図である。

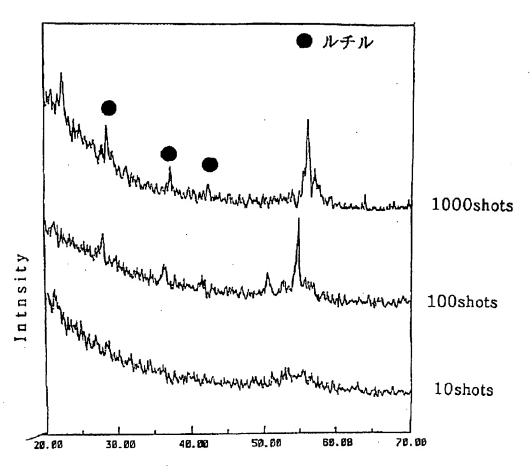
【図1】



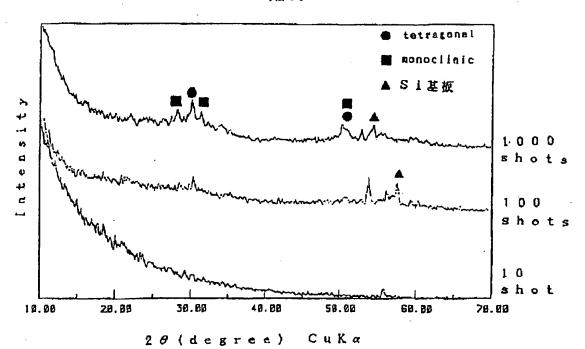
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IMAI HIROAKI

(54) PRODUCTION OF METALLIC OXIDE THIN FILM

PROBLEM TO BE SOLVED: To provide a method capable of forming thin film of crystallized transition metal oxide even on a substrate low in heat resistance such as plastics, free from the need of the use of expensive producing equipment and free from restriction by the shape and size of a substrate to be film-formed.

SOLUTION: The surface of the object to be coated is coated with a precursory coating soln. of metallic oxide obtd. by using the alkoxide of salt of transition metal as a starting raw material to form coating film on the surface of the object to be coated, and thereafter, the coating film is irradiated with ultraviolet light of ≥360 nm wavelength to crystallize the transition metal oxide forming the coating film.

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CLAIMS

[Claim(s)]

[Claim 1] The manufacture method of the metallic-oxide thin film which irradiates the ultraviolet radiation whose wavelength is 360nm or less to the application film, and is characterized by crystallizing the transition-metals oxide which forms the application film after applying the precursor application liquid of the metallic oxide obtained considering the alkoxide or salt of transition metals as a start raw material on the surface of a coated material and forming an application film in a coated material front face.

[Claim 2] The manufacture method of a metallic-oxide thin film according to claim 1 that transition metals are an IVa group element or Va group element.

[Claim 3] The manufacture method of a metallic-oxide thin film according to claim 1 or 2 that the light source of ultraviolet radiation irradiated to an application film is the 4 time wave of a high-pressure mercury lamp, a low-pressure mercury lamp, an ArF excimer laser, a KrF excimer laser, and an YAG laser or a 3 time wave, an excimer lamp, or synchrotron radiation.

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DETAILED DESCRIPTION

[Detailed Description of the Invention]

10001

[The technical field to which invention belongs] This invention relates to the manufacture method of the method of forming functional oxide thin films, such as electronic material, in the front face of substrates, such as glass, ceramics, a metal, and plastics, and the metallic-oxide thin film which forms the thin film of the transition-metals oxide crystallized without heat-treating especially.

T00021

[Description of the Prior Art] The compound which has the electrical property which was excellent as a dielectric material, an electrical conducting material, a semiconductor material, etc. exists in a transition-metals oxide mostly. The thin film of these transition-metals oxide is manufactured by the sol-gel method, the spraying thermal decomposition method, the sputtering method, the MOCVD method, etc.

[0003] It is related with the manufacture method of the transition-metals oxide thin film by the sol-gel method. An anatase crystallizes a titania film at the temperature of 400 degrees C, and transferring to a rutile phase by heat-treating at the temperature of 800 more degrees C is known. for example, a zirconia film It crystallizes by heat-treating at the temperature of 700 degrees C (a ceramic industry association magazine, 94,823 (1986) references). a niobium-oxide film It crystallizes by heat-treating at the temperature of 400 degrees C (a KYATARISHISU toe day (Catalysis Today), 16,495 (1993) references). an iron-oxide film crystallizing to a gamma ferric oxide (HEGUMA -- tight) at the temperature to 450 degrees C, and heat-treating at the temperature of 450 more degrees C or more -- alpha-iron oxide -- transferring (a journal OBU material science (J. Mater.Sci.) --) Crystallizing 26,497 (1991) reference and a zinc-oxide film at the temperature of 400 degrees C or more (the Ceramic Society of Japan treatise magazine, 104, 296 (1991) references) is reported, respectively. Moreover, it is reported that thin films, such as an iron oxide, chromia, a titania, and a zirconia, are formed about the manufacture method of the transition-metals oxide thin film by the spraying thermal decomposition method by using various kinds of metal salts as a start raw material (tin solid films (Thin Solid Films), 77, 81 (1981) references).

[Problem(s) to be Solved by the Invention] As described above, by the conventional method which forms the thin film of a transition-metals oxide with a general sol-gel method or a spraying part solution method, it is required to pyrolyze and remove the remains organic substance and a metal salt, and in order to crystallize a metallic oxide, the heat-treatment in an elevated temperature of 400 degrees C or more is indispensable as the result. For this reason, depending on the conventional method, the thin film of the crystallized transition-metals oxide was not able to be formed on the low base of thermal resistance, such as plastics.

[0005] Moreover, the sputtering method and the MOCVD method are based on a vacuum process, and, for this reason, have the trouble that an expensive manufacturing facility is required, and a manufacturing cost becomes high, and the configuration and size of a base which are going to form membranes have restrictions. Moreover, these methods also need heat-treatment of a substrate in many cases, in order to obtain a crystalline metallic-oxide thin film.

[0006] This invention is made in view of the above situations, can form the thin film of the crystallized transition-metals oxide also on the low base of thermal resistance, such as plastics, and aims at offering the manufacture method of a metallic-oxide thin film which is not restrained by the configuration or size of the base which the need of using an expensive manufacturing facility does not have, either, and is going to form membranes, either.

[0007]

[Means for Solving the Problem] Ultraviolet radiation was used for crystallizing the thin film of the transition-metals oxide gel formed by the sol-gel method as a means for attaining the above-mentioned purpose in this invention. That is, after invention concerning a claim I applies the precursor application liquid of the metallic oxide obtained considering the alkoxide or salt of transition metals as a start raw material on the surface of a coated material and forms an application film in a coated material front face, it irradiates the ultraviolet radiation whose wavelength is 360nm or less to the application film, and is characterized by crystallizing the transition-metals oxide which forms the application film.

[0008] By the manufacture method of invention concerning a claim 1, after applying the precursor application liquid of the metallic oxide obtained considering the alkoxide or salt of transition metals as a start raw material on the surface of a coated material and forming an application film, a transition-metals oxide is crystallized by irradiating the ultraviolet radiation whose

wavelength is 360nm or less to the application film. Therefore, since there is no need of performing heat-treatment in an elevated temperature for crystallization of a transition-metals oxide, it becomes possible to form the thin film of the crystallized transition-metals oxide also on a heat-resistant low base like plastics. In addition, although the mechanism of crystallization of the transition-metals oxide by irradiation of ultraviolet radiation is not clear, a thin film absorbs ultraviolet radiation, an atomic rearrangement is advanced by the energy and it is thought that a transition-metals oxide crystallizes.

[0009] Invention concerning a claim 2 is characterized by transition metals being an IVa group element or Va group element in the manufacture method according to claim 1.

[0010] Invention concerning a claim 3 is characterized by using the 4 time wave or 3 time wave of a high-pressure mercury lamp, a low-pressure mercury lamp, an ArF excimer laser, a KrF excimer laser, and an YAG laser, an excimer lamp, or synchrotron radiation in the manufacture method according to claim 1 or 2 as the light source of ultraviolet radiation irradiated to the thin film of metallic-oxide gel. Even if it uses only one kind of thing, you may use the light source combining two or more sorts of things.

[0011]

[Embodiments of the Invention] Hereafter, the suitable operation gestalt of this invention is explained.

[0012] By the manufacture method of the metallic-oxide thin film concerning this invention, the precursor application liquid (sol) of a metallic oxide is first prepared by using the alkoxide or salt of transition metals as a start raw material. Transition metals are for example, an IVa group element or Va group element. Especially the manufacture method of application liquid is so desirable that [when an application film (gel film) is formed, so that the remains organic substance in a film decreases, and] the crystallization temperature of the gel film by heat-treatment becomes low, although not limited. The manufacture method of application liquid is explained below.

[0013] As a metal alkoxide used as a start raw material, that whose carbon numbers of an alkoxyl group are 1-5 is used, and the thing of 2-4 is more preferably used for the carbon number of an alkoxyl group. Moreover, as a metal salt, organic acid chloride, such as mineral salt, such as a nitrate and a chloride, and an acetic acid, and the salt of beta-diketones, such as acetylacetonato, are used.

[0014] As a solvent in which a metal alkoxide or a metal salt is dissolved, aromatic series, such as acid amides, such as the cyclo ether, such as ketones, such as organic-acid ester, such as alcohols, such as a methanol, ethanol, propanol, and a butanol, and ethyl acetate, an acetonitrile, an acetone, and a methyl ethyl ketone, a tetrapod hydra furan (THF), and a dioxane, a formamide (FA), and N.N-dimethylformamide (DMF), a hydrocarbon, and toluene, etc. are used.

[0015] Moreover, you may make it contained in the solution containing a metal alkoxide for the purpose of stabilization of beta-diketone (RCOCH2COR';R and R' is an alkyl group or an alkoxyl group) which is a polydent compound, alkoxy alcohol, an alkanolamine, glycols, a glycerol, etc. of an alkoxide. As a beta-diketone, malonic esters, such as acetoacetic ester, such as an acetylacetone, an ethyl acetoacetate, and a methyl acetoacetate, and a diethyl malonate, etc. are used. As alkoxy alcohol, a 2-methoxyethanol, the 2-ethoxyethanol, 2-methoxy-2-propanol, etc. are used. A monoethanolamine, a diethanolamine, a triethanolamine, etc. are used as an alkanolamine. As glycols, monoalkyl ether and acetic ester of ethylene glycol, a diethylene glycol, a triethylene glycol and propylene glycols, or these compounds are used. These compounds are used independently, or are used together, and the kind is selected by a metal kind and the kind of alkoxyl group. Moreover, as for these compounds, it is desirable to contain the twice many 0.1-mol amount of twice - 1.5 mols as this of an alkoxide. In addition, alkoxy alcohols can also be used as a solvent.

[0016] The twice as many 0.05-mol twice - two-mol water of a metal alkoxide or a metal salt as this is used for hydrolysis of the solution containing a metal alkoxide or a metal salt, and twice as many 0.5-mol twice - 1.5-mol water as this is more preferably used for it. You may make it use an acid catalyst and/or a base catalyst for this hydrolysis, and organic acids, such as mineral acids, such as a hydrochloric acid, and an acetic acid, are preferably used for it. In addition, the diluted solution of an alkoxide is used depending on the kind of alkoxide. Moreover, when a metal salt is used as a start raw material, a reaction with the solvent of an alcoholic system is used effectively.

[0017] If the precursor application liquid (sol) of a metallic oxide is prepared by hydrolysis of the solution containing the alkoxide or salt of transition metals, the application liquid will be applied on the surface of a substrate, it will be dried, and an application film (metallic-oxide gel film) will be formed in a substrate front face. Especially the method of application of application liquid is not limited, but the dip coating method usually performed, the spin coat method, the flow coat method, the bar coat method, an ultrasonic atomizing process, etc. are used. In addition, the crystallization temperature at the time of heat-treating is so desirable that there is little remains organic amount of resources in the film as a gel film obtained at this time as described above as a low.

[0018] If an application film is formed in a substrate front face, the ultraviolet radiation whose wavelength is 360nm or less will be irradiated to the application film. If irradiation to the ultraviolet radiation whose wavelength is 360nm or less is possible as the light source of ultraviolet radiation, although it will be used according to the metallic-oxide thin film which does not ask the kind but is made into the purpose, choosing suitably, a high-pressure mercury lamp, a low-pressure mercury lamp, an excimer lamp, an ArF excimer laser, a KrF excimer laser, a 4 times many YAG laser [as this] wave or a 3 time wave, synchrotron radiation, etc. are used, for example. Moreover, it is also possible to use it combining two or the thing beyond it among these light sources. It is also possible to heat a substrate, to put a substrate under reduced pressure, or to control atmosphere (an oxidizing atmosphere or non-oxidizing atmosphere) according to the purpose, in the case of the ultraviolet radiation irradiation to this application film. Moreover, the irradiation intensity and the shots per hour of ultraviolet

radiation are suitably chosen according to the kind of application film, composition, etc. By irradiating ultraviolet radiation to an application film, the metallic-oxide gel which forms the application film is crystallized, and the thin film of a transition-metals oxide is formed on the surface of a substrate.

[Example] Next, the example which applied this invention concretely is explained.

[0020] [Example 1] The pentaethoxy tantalum was dissolved in ethanol so that the solid-content concentration of a metallic oxide might become 3 % of the weight, and application liquid was prepared. After applying this application liquid on a silica substrate using a spin coater (2,000rpmx 15 seconds), it was made to dry with an oven with a temperature of 100 degrees C for 1 hour, and the application film was formed on the silica substrate. The ArF excimer laser (193nm, 2,300 shot of 25 mJ/cm) was irradiated at the obtained application film. Thereby, the crystalline tantalum oxide (Ta 2O5) thin film was obtained. The thin film X diffraction pattern of the obtained thin film is shown in drawing 1.

[0021] [Example 2] Pentaethoxy niobium was dissolved in ethanol so that the solid-content concentration of a metallic oxide might become 3 % of the weight, and application liquid was prepared. After applying this application liquid on a silica substrate using a spin coater (2,000rpmx 15 seconds), it was made to dry with an oven with a temperature of 100 degrees C for 1 hour, and the application film was formed on the silica substrate. The ArF excimer laser (193nm, 2,300 shot of 25 mJ/cm) was irradiated at the obtained application film. Thereby, the crystalline niobium-oxide (Nb 2O5) thin film was obtained.

[0022] [Example 3] Dissolved tetraisopropoxy titanium in the 2-methoxyethanol, added the 0.1 convention hydrochloric acid containing the water of mols [titanium] in the 2-methoxyethanol solution, the solution was made to understand an added water part, and application liquid was prepared. It was made for the solid-content concentration of the metallic oxide in this application liquid to become 3 % of the weight. After applying this application liquid on a silicon substrate using a spin coater (2,000rpmx 15 seconds), it was made to dry with an oven with a temperature of 100 degrees C for 1 hour, and the application film was formed on the silicon substrate. The 4 time wave (266nm, 10 mJ/cm2) of an YAG laser was changed, and the irradiation shots per hour was irradiated on it at the obtained application film. Thereby, the rutile (TiO2) thin film was obtained. When an irradiation shots per hour was 100 shots, the rutile diffraction peak was accepted. Change of the thin film X diffraction pattern of the obtained thin film is shown in drawing 2.

[0023] [Example 4] It added to dehydrated ethanol so that the solid-content concentration of a metallic oxide might become 3 % of the weight, and a titanium tetrachloride will be agitated for one day, and was dissolved, and application liquid was prepared. After applying this application liquid on a silicon substrate using a spin coater (2,000rpmx 15 seconds), it was made to dry with an oven with a temperature of 100 degrees C for 1 hour, and the application film was formed on the silicon substrate. The 4 time wave (266nm, 2,300 shot of 10 mJ/cm) of an YAG laser was irradiated at the obtained application film. Thereby, the rutile (TiO2) thin film was obtained like the above-mentioned example 3.

[0024] [Example 5] Dissolved tetra-N-butoxyzirconium in the 2-methoxyethanol, added the acetylacetone of mols [zirconium] in the 2-methoxyethanol solution, added the 0.1 convention hydrochloric acid containing the water of mols [zirconium] in the 2-methoxyethanol solution further, the solution was made to understand an added water part, and application liquid was prepared. It was made for the solid-content concentration of the metallic oxide in this application liquid to become 3 % of the weight. After applying this application liquid on a silicon substrate using a spin coater (2,000rpmx 15 seconds), it was made to dry with an oven with a temperature of 100 degrees C for 1 hour, and the application film was formed on the silicon substrate. The ArF excimer laser (193nm, 2,100 shot of 25 mJ/cm) was irradiated at the obtained application film. Thereby, the cubic zirconia (ZrO2) thin film was obtained. Furthermore, when 1,000 shots irradiated an ArF excimer laser at an application film, the monoclinic system which is the parent phase of a zirconia was accepted. Change of the thin film X diffraction pattern of the obtained thin film is shown in drawing 3.

[0025] [Example 6] Zirconium tetrapod acetylacetonato was dissolved in the methanol so that the solid-content concentration of a metallic oxide might become 3 % of the weight, and application liquid was prepared. After applying this application liquid on a silicon substrate using a spin coater (2,000rpmx 15 seconds), left it in the atmosphere of 60% of humidity for 3 hours, it was made to dry in oven with a temperature of 100 degrees C after that for 1 hour, and the application film was formed on the silicon substrate. The ArF excimer laser (193nm, 2 or 1,000 shot of 25 mJ/cm) was irradiated at the obtained application film. Thereby, the zirconia (ZrO2) thin film of a cubic and monoclinic system was obtained like the above-mentioned example 5.

[0026] [Examples 1-6 of comparison] The crystalline metallic-oxide thin film was produced by heat-treating the application film (metallic-oxide gel film) obtained in the above-mentioned examples 1-6. Each heat-treatment temperature at this time and the obtained crystal phase are collectively shown in Table 1.

[0027]

[Table 1]

3/11/03 3:41 PM

| | 加熱処理温度(℃) | 紺 晶 相 |
|-------|----------------|----------------------|
| 比較例1 | 4 5 0 | Та:О. |
| 比較例 2 | 450 | Nb.O. |
| 比較例 3 | 4 0 0 7 0 0 | アナターゼ ルチル単相 |
| 比較例4 | 5 0 0 7 0 0 | アナターゼ ルチル単相 |
| 比較例 5 | 5 0 0 8 0 0 | 立方品ジルコニア 単斜品ジルコニア |
| 比較例6 | 5 0 0 | 立方晶ジルコニア |

[0028] As shown in Table 1, in order to obtain a crystalline metallic-oxide thin film, heat-treatment at the temperature of 400 degrees C or more was required. In order to obtain the rutile single phase film and monoclinic system zirconia film which were especially obtained in the example 3 - the example 6, respectively, heat-treatment at the temperature of 700 degrees C or more was required.

[0029] In addition, this invention cannot be overemphasized by that it can apply when it is not limited to formation of the transition-metals oxide thin film shown in the above-mentioned example and forms transition-metals oxide thin films other than the above without heat-treatment. Thus, since a crystalline transition-metals oxide thin film can be formed without heat-treating, according to the method of this invention, by the conventional method, formation of the transition-metals oxide thin film in the multilayer which can form a transition-metals oxide thin film on the substrate inferior to thermal resistance, such as impossible plastics, and contains the organic substance is also attained.

[Effect of the Invention] According to the manufacture method of invention concerning a claim 1 or a claim 3, the thin film of the crystallized transition-metals oxide can be obtained at the temperature near a room temperature. Therefore, it is possible to form a crystalline transition-metals oxide thin film also on the low substrate of thermal resistance, such as plastics. Moreover, in order to enforce this manufacture method, the need of using an expensive manufacturing facility is not restrained by the configuration or size of a base which there are not, can hold down a manufacturing cost low, and are going to form membranes.

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TECHNICAL FIELD

[The technical field to which invention belongs] This invention relates to the manufacture method of the method of forming functional oxide thin films, such as electronic material, in the front face of substrates, such as glass, ceramics, a metal, and plastics, and the metallic-oxide thin film which forms the thin film of the transition-metals oxide crystallized without heat-treating especially.

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PRIOR ART

[Description of the Prior Art] The compound which has the electrical property which was excellent as a dielectric material, an electrical conducting material, a semiconductor material, etc. exists in a transition-metals oxide mostly. The thin film of these transition-metals oxide is manufactured by the sol-gel method, the spraying thermal decomposition method, the sputtering method, the MOCVD method, etc.

[0003] It is related with the manufacture method of the transition-metals oxide thin film by the sol-gel method. An anatase crystallizes a titania film at the temperature of 400 degrees C, and transferring to a rutile phase by heat-treating at the temperature of 800 more degrees C is known. for example, a zirconia film It crystallizes by heat-treating at the temperature of 700 degrees C (a ceramic industry association magazine, 94,823 (1986) references). a niobium-oxide film It crystallizes by heat-treating at the temperature of 400 degrees C (a KYATARISHISU toe day (Catalysis Today), 16,495 (1993) references). an iron-oxide film crystallizing to a gamma ferric oxide (HEGUMA -- tight) at the temperature to 450 degrees C, and heat-treating at the temperature of 450 more degrees C or more -- alpha-iron oxide -- transferring (a journal OBU material science (J. Mater.Sci.) --) Crystallizing 26,497 (1991) reference and a zinc-oxide film at the temperature of 400 degrees C or more (the Ceramic Society of Japan treatise magazine, 104, 296 (1991) references) is reported, respectively. Moreover, it is reported that thin films, such as an iron oxide, chromia, a titania, and a zirconia, are formed about the manufacture method of the transition-metals oxide thin film by the spraying thermal decomposition method by using various kinds of metal salts as a start raw material (tin solid films (Thin Solid Films), 77, 81 (1981) references).

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EFFECT OF THE INVENTION

[Effect of the Invention] According to the manufacture method of invention concerning a claim 1 or a claim 3, the thin film of the crystallized transition-metals oxide can be obtained at the temperature near a room temperature. Therefore, it is possible to form a crystalline transition-metals oxide thin film also on the low substrate of thermal resistance, such as plastics. Moreover, in order to enforce this manufacture method, the need of using an expensive manufacturing facility is not restrained by the configuration or size of a base which there are not, can hold down a manufacturing cost low, and are going to form membranes.

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TECHNICAL PROBLEM

[Problem(s) to be Solved by the Invention] As described above, by the conventional method which forms the thin film of a transition-metals oxide with a general sol-gel method or a spraying part solution method, it is required to pyrolyze and remove the remains organic substance and a metal salt, and in order to crystallize a metallic oxide, the heat-treatment in an elevated temperature of 400 degrees C or more is indispensable as the result. For this reason, depending on the conventional method, the thin film of the crystallized transition-metals oxide was not able to be formed on the low base of thermal resistance, such as plastics.

[0005] Moreover, the sputtering method and the MOCVD method are based on a vacuum process, and, for this reason, have the trouble that an expensive manufacturing facility is required, and a manufacturing cost becomes high, and the configuration and size of a base which are going to form membranes have restrictions. Moreover, these methods also need heat-treatment of a substrate in many cases, in order to obtain a crystalline metallic-oxide thin film.

[0006] This invention is made in view of the above situations, can form the thin film of the crystallized transition-metals oxide also on the low base of thermal resistance, such as plastics, and aims at offering the manufacture method of a metallic-oxide thin film which is not restrained by the configuration or size of the base which the need of using an expensive manufacturing facility does not have, either, and is going to form membranes, either.

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MEANS

[Means for Solving the Problem] Ultraviolet radiation was used for crystallizing the thin film of the transition-metals oxide gel formed by the sol-gel method as a means for attaining the above-mentioned purpose in this invention. That is, after invention concerning a claim 1 applies the precursor application liquid of the metallic oxide obtained considering the alkoxide or salt of transition metals as a start raw material on the surface of a coated material and forms an application film in a coated material front face, it irradiates the ultraviolet radiation whose wavelength is 360nm or less to the application film, and is characterized by crystallizing the transition-metals oxide which forms the application film.

[0008] By the manufacture method of invention concerning a claim 1, after applying the precursor application liquid of the metallic oxide obtained considering the alkoxide or salt of transition metals as a start raw material on the surface of a coated material and forming an application film, a transition-metals oxide is crystallized by irradiating the ultraviolet radiation whose wavelength is 360nm or less to the application film. Therefore, since there is no need of performing heat-treatment in an elevated temperature for crystallization of a transition-metals oxide, it becomes possible to form the thin film of the crystallized transition-metals oxide also on a heat-resistant low base like plastics. In addition, although the mechanism of crystallization of the transition-metals oxide by irradiation of ultraviolet radiation is not clear, a thin film absorbs ultraviolet radiation, an atomic rearrangement is advanced by the energy and it is thought that a transition-metals oxide crystallizes.

[0009] Invention concerning a claim 2 is characterized by transition metals being an IVa group element or Va group element in the manufacture method according to claim 1.

[0010] Invention concerning a claim 3 is characterized by using the 4 time wave or 3 time wave of a high-pressure mercury lamp, a low-pressure mercury lamp, an ArF excimer laser, a KrF excimer laser, and an YAG laser, an excimer lamp, or synchrotron radiation in the manufacture method according to claim 1 or 2 as the light source of ultraviolet radiation irradiated to the thin film of metallic-oxide gel. Even if it uses only one kind of thing, you may use the light source combining two or more sorts of things.

[0011]

[Embodiments of the Invention] Hereafter, the suitable operation form of this invention is explained.

[0012] By the manufacture method of the metallic-oxide thin film concerning this invention, the precursor application liquid (sol) of a metallic oxide is first prepared by using the alkoxide or salt of transition metals as a start raw material. Transition metals are for example, an IVa group element or Va group element. Especially the manufacture method of application liquid is so desirable that [when an application film (gel film) is formed, so that the remains organic substance in a film decreases, and] the crystallization temperature of the gel film by heat-treatment becomes low, although not limited. The manufacture method of application liquid is explained below.

[0013] As a metal alkoxide used as a start raw material, that whose carbon numbers of an alkoxyl group are 1-5 is used, and the thing of 2-4 is more preferably used for the carbon number of an alkoxyl group. Moreover, as a metal salt, organic acid chloride, such as mineral salt, such as a nitrate and a chloride, and an acetic acid, and the salt of beta-diketones, such as acetylacetonato, are used.

[0014] As a solvent in which a metal alkoxide or a metal salt is dissolved, aroma groups, such as acid amides, such as the cyclo ether, such as ketones, such as organic-acid ester, such as alcohols, such as a methanol, ethanol, propanol, and a butanol, and ethyl acetate, an acetonitrile, an acetone, and a methyl ethyl ketone, a tetrapod hydra furan (THF), and a dioxane, a formamide (FA), and N.N-dimethylformamide (DMF), a hydrocarbon, and toluene, etc. are used.

[0015] Moreover, you may make it contained in the solution containing a metal alkoxide for the purpose of stabilization of beta-diketone (RCOCH2COR';R and R' is an alkyl group or an alkoxyl group) which is a polydent compound, alkoxy alcohol, an alkanolamine, glycols, a glycerol, etc. of an alkoxide. As a beta-diketone, malonic esters, such as acetoacetic ester, such as an acetylacetone, an ethyl acetoacetate, and a methyl acetoacetate, and a diethyl malonate, etc. are used. As alkoxy alcohol, a 2-methoxyethanol, a 2-ethoxyethanol, 2-methoxy-2-propanol, etc. are used. A monoethanolamine, a diethanolamine, a triethanolamine, etc. are used as an alkanolamine. As glycols, monoalkyl ether and acetic ester of ethylene glycol, a diethylene glycol, a triethylene glycol and propylene glycols, or these compounds are used. These compounds are used independently, or are used together, and the kind is selected by a metal kind and the kind of alkoxyl group. Moreover, as for these compounds, it is desirable to contain the twice many 0.1-mol amount of twice - 1.5 mols as this of an alkoxide. In addition, alkoxy alcohols can also be used as a solvent.

[0016] The twice as many 0.05-mol twice - two-mol water of a metal alkoxide or a metal salt as this is used for hydrolysis of

the solution containing a metal alkoxide or a metal salt, and twice as many 0.5-mol twice - 1.5-mol water as this is more preferably used for it. You may make it use an acid catalyst and/or a base catalyst for this hydrolysis, and organic acids, such as mineral acids, such as a hydrochloric acid, and an acetic acid, are preferably used for it. In addition, the diluted solution of an alkoxide is used depending on the kind of alkoxide. Moreover, when a metal salt is used as a start raw material, a reaction with the solvent of an alcoholic system is used effectively.

[0017] If the precursor application liquid (sol) of a metallic oxide is prepared by hydrolysis of the solution containing the alkoxide or salt of transition metals, the application liquid will be applied on the surface of a substrate, it will be dried, and an application film (metallic-oxide gel film) will be formed in a substrate front face. Especially the method of application of application liquid is not limited, but the dip coating method usually performed, the spin coat method, the flow coat method, the bar coat method, an ultrasonic atomizing process, etc. are used. In addition, as a gel film obtained at this time, it is so desirable that [as described above, so that there is little remains organic amount of resources in the film, and] the crystallization temperature at the time of heat-treating is low.

[0018] If an application film is formed in a substrate front face, the ultraviolet radiation whose wavelength is 360nm or less will be irradiated to the application film. If irradiation to the ultraviolet radiation whose wavelength is 360nm or less is possible as the light source of ultraviolet radiation, although it will be used according to the metallic-oxide thin film which does not ask the kind but is made into the purpose, choosing suitably, a high-pressure mercury lamp, a low-pressure mercury lamp, an excimer lamp, an ArF excimer laser, a KrF excimer laser, a 4 times many YAG laser [as this] wave or a 3 time wave, synchrotron radiation, etc. are used, for example. Moreover, it is also possible to use it combining two or the thing beyond it among these light sources. It is also possible to heat a substrate, to put a substrate under reduced pressure, or to control atmosphere (an oxidizing atmosphere or non-oxidizing atmosphere) according to the purpose, in the case of the ultraviolet radiation irradiation to this application film. Moreover, the irradiation intensity and the shots per hour of ultraviolet radiation are suitably chosen according to the kind of application film, composition, etc. By irradiating ultraviolet radiation to an application film, the metallic-oxide gel which forms the application film is crystallized, and the thin film of a transition-metals oxide is formed on the surface of a substrate.

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EXAMPLE

[Example] Next, the example which applied this invention concretely is explained.

[0020] [Example 1] The pentaethoxy tantalum was dissolved in ethanol so that the solid-content concentration of a metallic oxide might become 3 % of the weight, and application liquid was prepared. After applying this application liquid on a silica substrate using a spin coater (2,000rpmx 15 seconds), it was made to dry with an oven with a temperature of 100 degrees C for I hour, and the application film was formed on the silica substrate. The ArF excimer laser (193nm, 2,300 shot of 25 mJ/cm) was irradiated at the obtained application film. Thereby, the crystalline tantalum oxide (Ta 2O5) thin film was obtained. The thin film X diffraction pattern of the obtained thin film is shown in drawing 1.

[0021] [Example 2] Pentaethoxy niobium was dissolved in ethanol so that the solid-content concentration of a metallic oxide might become 3 % of the weight, and application liquid was prepared. After applying this application liquid on a silica substrate using a spin coater (2,000rpmx 15 seconds), it was made to dry with an oven with a temperature of 100 degrees C for 1 hour, and the application film was formed on the silica substrate. The ArF excimer laser (193nm, 2,300 shot of 25 mJ/cm) was irradiated at the obtained application film. Thereby, the crystalline niobium-oxide (Nb 2O5) thin film was obtained.

[0022] [Example 3] Dissolved tetraisopropoxy titanium in the 2-methoxyethanol, added the decinormal hydrochloric acid containing the water of mols [titanium] in the 2-methoxyethanol solution, the solution was made to understand an added water part, and application liquid was prepared. It was made for the solid-content concentration of the metallic oxide in this application liquid to become 3 % of the weight. After applying this application liquid on a silicon substrate using a spin coater (2,000rpmx 15 seconds), it was made to dry with an oven with a temperature of 100 degrees C for 1 hour, and the application film was formed on the silicon substrate. The 4 time wave (266nm, 10 mJ/cm2) of an YAG laser was changed, and the irradiation shots per hour was irradiated on it at the obtained application film. Thereby, the rutile (TiO2) thin film was obtained. When an irradiation shots per hour was 100 shots, the rutile diffraction peak was accepted. Change of the thin film X diffraction pattern of the obtained thin film is shown in drawing 2.

[0023] [Example 4] It added to dehydrated ethanol so that the solid-content concentration of a metallic oxide might become 3 % of the weight, and a titanium tetrachloride will be agitated for one day, and was dissolved, and application liquid was prepared. After applying this application liquid on a silicon substrate using a spin coater (2,000rpmx 15 seconds), it was made to dry with an oven with a temperature of 100 degrees C for 1 hour, and the application film was formed on the silicon substrate. The 4 time wave (266nm, 2,300 shot of 10 mJ/cm) of an YAG laser was irradiated at the obtained application film. Thereby, the rutile (TiO2) thin film was obtained like the above-mentioned example 3.

[0024] [Example 5] Dissolved tetra-N-butoxyzirconium in the 2-methoxyethanol, added the acetylacetone of mols [zirconium] in the 2-methoxyethanol solution, added the decinormal hydrochloric acid containing the water of mols [zirconium] in the 2-methoxyethanol solution further, the solution was made to understand an added water part, and application liquid was prepared. It was made for the solid-content concentration of the metallic oxide in this application liquid to become 3 % of the weight. After applying this application liquid on a silicon substrate using a spin coater (2,000rpmx 15 seconds), it was made to dry with an oven with a temperature of 100 degrees C for 1 hour, and the application film was formed on the silicon substrate. The ArF excimer laser (193nm, 2,100 shot of 25 mJ/cm) was irradiated at the obtained application film. Thereby, the cubic zirconia (ZrO2) thin film was obtained. Furthermore, when 1,000 shots irradiated an ArF excimer laser at an application film, the monoclinic system which is the parent phase of a zirconia was accepted. Change of the thin film X diffraction pattern of the obtained thin film is shown in drawing 3.

[0025] [Example 6] Zirconium tetrapod acetylacetonato was dissolved in the methanol so that the solid-content concentration of a metallic oxide might become 3 % of the weight, and application liquid was prepared. After applying this application liquid on a silicon substrate using a spin coater (2,000rpmx 15 seconds), left it in the atmosphere of 60% of humidity for 3 hours, it was made to dry in oven with a temperature of 100 degrees C after that for 1 hour, and the application film was formed on the silicon substrate. The ArF excimer laser (193nm, 2 or 1,000 shot of 25 mJ/cm) was irradiated at the obtained application film. Thereby, the zirconia (ZrO2) thin film of a cubic and monoclinic system was obtained like the above-mentioned example 5.

[0026] [Examples 1-6 of comparison] The crystalline metallic-oxide thin film was produced by heat-treating the application film (metallic-oxide gel film) obtained in the above-mentioned examples 1-6. Each heat-treatment temperature at this time and the obtained crystal phase are collectively shown in Table 1.

[0027] [Table 1]

| [Tuble 1] | | |
|------------|----------------|----------------------|
| | 加無処理温度(℃) | 結 晶 相 |
| 比較例1 | . 450 | T a 10. |
| 比較例 2 | 4 5 0 | Nb.O. |
| 比較例3 | 4 0 0 7 0 0 | アナターゼ ルチル単相 |
| 比較例4 | 5 0 0 7 0 0 | アナターゼ ルチル単相 |
| 比較例 5 | 5 0 0 8 0 0 | 立方品ジルコニア 単斜品ジルコニア |
| 比較例6 | '500 | 立方晶ジルコニア |

[0028] As shown in Table 1, in order to obtain a crystalline metallic-oxide thin film, heat-treatment at the temperature of 400 degrees C or more was required. In order to obtain the rutile single phase film and monoclinic system zirconia film which were especially obtained in the example 3 - the example 6, respectively, heat-treatment at the temperature of 700 degrees C or more was required.

[0029] In addition, this invention cannot be overemphasized by that it can apply when it is not limited to formation of the transition-metals oxide thin film shown in the above-mentioned example and forms transition-metals oxide thin films other than the above without heat-treatment. Thus, since a crystalline transition-metals oxide thin film can be formed without heat-treating, according to the method of this invention, by the conventional method, formation of the transition-metals oxide thin film in the multilayer which can form a transition-metals oxide thin film on the substrate inferior to thermal resistance, such as impossible plastics, and contains the organic substance is also attained.

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DESCRIPTION OF DRAWINGS

[Brief Description of the Drawings]

[Drawing 1] It is drawing showing the thin film X diffraction pattern of the tantalum oxide thin film obtained by the manufacture method concerning this invention.

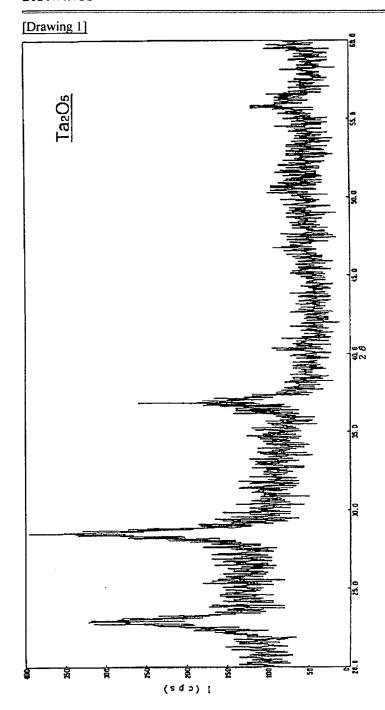
[Drawing 2] It is drawing showing change of the thin film X diffraction pattern of the rutile thin film similarly obtained by the manufacture method concerning this invention.

[Drawing 3] It is drawing showing change of the thin film X diffraction pattern of the zirconia thin film similarly obtained by the manufacture method concerning this invention.

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DRAWINGS



[Drawing 2]

